IN THE CLAIMS:

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1. (Previously Presented) A plasma treatment apparatus comprising:

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- a plasma generation unit comprising a first electrode and a plurality of second electrodes opposed to the first electrode;
- a gas supply unit for blowing a process gas into a space between the first electrode and the plurality of second electrodes; and
- a unit for selectively applying a voltage to at least one electrode among the plurality of second electrodes,

wherein the plurality of second electrodes are arranged linearly in one line or a plurality of lines.

- 2. (Previously Presented) A plasma treatment apparatus comprising:
- a plasma generation unit comprising a first electrode and a plurality of second electrodes opposed to the first electrode;
- a gas supply unit for blowing a process gas into a space between the first electrode and the plurality of second electrodes; and
- a unit for selectively applying a voltage to at least one electrode among the plurality of second electrodes,

wherein the plurality of second electrodes are arranged linearly in one line or a plurality of lines; and

wherein at least one of the plurality of second electrodes has a length of equal to or less than 1 mm on a side of an object to be treated.

- 3. (Previously Presented) A plasma treatment apparatus comprising:
- a plasma generation unit comprising a first electrode and a plurality of second electrodes opposed to the first electrode for forming a pattern on an object to be treated;
- a gas supply unit for blowing a process gas into a space between the first electrode and the plurality of second electrodes; and
- a unit for selectively applying a voltage to at least one electrode among the plurality of second electrodes,

wherein the plurality of second electrodes are arranged linearly in one line or a plurality of lines; and

wherein at least one of the plurality of second electrodes has a length of equal to or less than a square of a line width of the pattern on a side of the object to be treated.

- 4. (Original) A plasma treatment apparatus according to claim 3, wherein the pattern is a wiring pattern.
- 5. (Previously Presented) A plasma treatment apparatus according to claim 2 further comprising a unit for positioning one of the plurality of plasma generation units to the object to be treated.
- 6. (Previously Presented) A plasma treatment apparatus according to claim 3 further comprising a unit for positioning one of the plurality of plasma generation units to the pattern on the object to be treated.
- 7. (Previously Presented) A plasma treatment apparatus according to claim 1, wherein a relatively scanning of the plurality of plasma generation units is synchronized with the application of the voltage to the predetermined electrode.
- 8. (Previously Presented) A plasma treatment apparatus according to claim 2, wherein a relatively scanning of the plurality of plasma generation units is synchronized with the application of the voltage to the predetermined electrode.
- 9. (Previously Presented) A plasma treatment apparatus according to claim 3, wherein a relatively scanning of the plurality of plasma generation units is synchronized with the application of the voltage to the predetermined electrode.
- 10. (Previously Presented) A plasma treatment apparatus according to claim 1, wherein the plurality of second electrodes are processed by using a focused ion beam apparatus, photolithography, or a laser lithography apparatus.

- 11. (Previously Presented) A plasma treatment apparatus according to claim 2, wherein the plurality of second electrodes are processed by using a focused ion beam apparatus, photolithography, or a laser lithography apparatus.
- 12. (Previously Presented) A plasma treatment apparatus according to claim 3, wherein the plurality of second electrodes are processed by using a focused ion beam apparatus, photolithography, or a laser lithography apparatus.
- 13. (Previously Presented) A plasma treatment apparatus according to claim 1, wherein the first electrode and the plurality of second electrodes are covered with a dielectric.
- 14. (Previously Presented) A plasma treatment apparatus according to claim 2, wherein the first electrode and the plurality of second electrodes are covered with a dielectric.
- 15. (Previously Presented) A plasma treatment apparatus according to claim 3, wherein the first electrode and the plurality of second electrodes are covered with a dielectric.
- 16. (Previously Presented) A plasma treatment apparatus according to claim 1, wherein the voltage is applied to the predetermined electrode for performing a film formation, an etching treatment, or a surface modification over an object to be treated.
- 17. (Previously Presented) A plasma treatment apparatus according to claim 2, wherein the voltage is applied to the predetermined electrode for performing a film formation, an etching treatment, or a surface modification over an object to be treated.
- 18. (Previously Presented) A plasma treatment apparatus according to claim 3, wherein the forming of the pattern is performed under atmospheric pressure or under pressure approximate to atmospheric pressure.

19 (Previously Presented) A plasma treatment apparatus according to claim 1 further comprising a stage to which an object to be treated is fixed,

wherein a scanning of the stage is synchronized with the application of he voltage to the predetermined electrode.

20. (Previously Presented) A plasma treatment apparatus according to claim 2 further comprising a stage to which the object is fixed,

wherein a scanning of the stage is synchronized with the application of the voltage to the predetermined electrode.

21. (Previously Presented) A plasma treatment apparatus according to claim 3 further comprising a stage to which the object is fixed,

wherein a scanning of the stage is synchronized with the application of the voltage to the predetermined electrode.

- 22. (Previously Presented) A plasma treatment apparatus according to claim 16, wherein the film formation, the etching treatment, or the surface modification is performed under atmospheric pressure or under pressure approximate to atmospheric pressure.
- 23. (Previously Presented) A plasma treatment apparatus according to claim 17, wherein the film formation, the etching treatment, or the surface modification is performed under atmospheric pressure or under pressure approximate to atmospheric pressure.
 - 24. (Previously Presented) A plasma treatment apparatus comprising:
- a plurality of plasma generation units each comprising a first electrode and a plurality of second electrodes;
- a gas supply unit for blowing a process gas into a space between the first electrode and the plurality of second electrodes; and
- a unit for selectively applying a voltage to at least one electrode among the plurality of second electrodes,

wherein the plurality of plasma generation units are arranged linearly in one line or a plurality of lines.

- 25. (Previously Presented) A plasma treatment apparatus according to claim 24, wherein a relatively scanning of the plurality of plasma generation units is synchronized with the application of the voltage to the predetermined electrode.
- 26. (Previously Presented) A plasma treatment apparatus according to claim 24, wherein the plurality of second electrodes are processed by using a focused ion beam apparatus, photolithography, or a laser lithography apparatus.
- 27. (Previously Presented) A plasma treatment apparatus according to claim 24, wherein the first electrode and the plurality of second electrodes are covered with a dielectric.
- 28. (Previously Presented) A plasma treatment apparatus according to claim 24, wherein the voltage is applied to the predetermined electrode for performing a film formation, an etching treatment, or a surface modification over an object to be treated.
- 29. (Previously Presented) A plasma treatment apparatus according to claim 24 further comprising a stage to which an object to be treated is fixed,

wherein a scanning of the stage is synchronized with the application of he voltage to the predetermined electrode.

- 30. (Previously Presented) A plasma treatment apparatus according to claim 28, wherein the film formation, the etching treatment, or the surface modification is performed under atmospheric pressure or under pressure approximate to atmospheric pressure.
 - 31. (Previously Presented) A plasma treatment apparatus comprising:
- a plasma generation unit comprising a first electrode and a plurality of second electrodes opposed to the first electrode;
- a gas supply unit for blowing a process gas to a substrate to be treated through a space between the first electrode and the plurality of second electrodes; and
- a unit for selectively applying a voltage to at least one electrode among the plurality of second electrodes,

wherein the plurality of second electrodes are arranged linearly in one line or a plurality of lines.

- 32. (Previously Presented) A plasma treatment apparatus according to claim 31, wherein a relatively scanning of the plurality of plasma generation units is synchronized with the application of the voltage to the predetermined electrode.
- 33. (Previously Presented) A plasma treatment apparatus according to claim 31, wherein the plurality of second electrodes are processed by using a focused ion beam apparatus, photolithography, or a laser lithography apparatus.
- 34. (Previously Presented) A plasma treatment apparatus according to claim 31, wherein the first electrode and the plurality of second electrodes are covered with a dielectric.
- 35. (Previously Presented) A plasma treatment apparatus according to claim 31, wherein the voltage is applied to the predetermined electrode for performing a film formation, an etching treatment, or a surface modification over an object to be treated.
- 36. (Previously Presented) A plasma treatment apparatus according to claim 31 further comprising a stage to which an object to be treated is fixed,

wherein a scanning of the stage is synchronized with the application of he voltage to the predetermined electrode.

- 37. (Previously Presented) A plasma treatment apparatus according to claim 35, wherein the film formation, the etching treatment, or the surface modification is performed under atmospheric pressure or under pressure approximate to atmospheric pressure.
 - 38. (New) A plasma treatment apparatus comprising:
- a plasma generation unit comprising a first electrode and a plurality of second electrodes opposed to the first electrode;
- a gas supply unit for blowing a process gas through a first space and a second a second space continuously, the first space being between the first electrode and a substrate

and the second space being between the plurality of second electrodes and the substrate; and a unit for selectively applying a voltage to at least one electrode among the plurality of second electrodes,

wherein the plurality of second electrodes are arranged linearly in one line or a plurality of lines.

- 39. (New) A plasma treatment apparatus according to claim 38, wherein a relatively scanning of the plurality of plasma generation units is synchronized with the application of the voltage to the predetermined electrode.
- 40. (New) A plasma treatment apparatus according to claim 38, wherein the plurality of second electrodes are processed by using a focused ion beam apparatus, photolithography, or a laser lithography apparatus.
- 41. (New) A plasma treatment apparatus according to claim 38, wherein the first electrode and the plurality of second electrodes are covered with a dielectric.
- 42. (New) A plasma treatment apparatus according to claim 38, wherein the voltage is applied to the predetermined electrode for performing a film formation, an etching treatment, or a surface modification over an object to be treated.
- 43. (New) A plasma treatment apparatus according to claim 38 further comprising a stage to which an object to be treated is fixed,

wherein a scanning of the stage is synchronized with the application of he voltage to the predetermined electrode.

44. (New) A plasma treatment apparatus according to claim 42, wherein the film formation, the etching treatment, or the surface modification is performed under atmospheric pressure or under pressure approximate to atmospheric pressure.